











D-408. Exam Schedule

Mon, 24 Dec	14:30 — 16:05	TEST Interaction of RF Electromagnetic Radiation with Semiconductor Electronics Materials (Physics Principals)  M18-416  Shurenkov V.V.
Wed, 26 Dec	11:05 — 12:40	ATT Reliability and Radiation Resistance of Microelectronic Devices and Systems  M17-416  Zebrev G.I.
Fri, 28 Dec	08:30 — 10:05	ATT Reliability and Radiation Resistance of Microelectronic Devices and Systems  M18-403  Zebrev G.I.
Mon, 14 Jan	09:00 — 13:00	EXAM Reliability and Radiation Resistance of Microelectronic Devices and Systems  M17-416  Zebrev G.I.
Fri, 25 Jan	09:00 — 13:00	EXAM Reliability and Radiation Resistance of Microelectronic Devices and Systems  M18-403  Zebrev G.I.